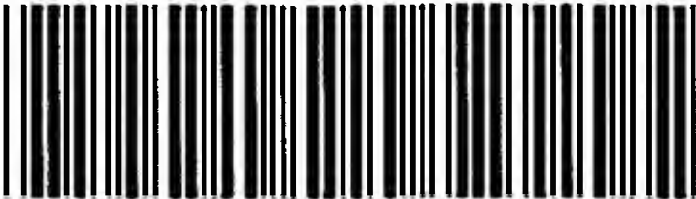


<div>Search Notes</div> <div></div>	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/605,785	LEE ET AL.	
	Examiner	Art Unit	
	Ryan Hsu	3714	

SEARCHED			
Class	Subclass	Date	Examiner
473	202	5/9/2006	RH
473	198, 201	5/9/2006	RH
473	221-226	5/9/2006	RH
473	231-233	5/9/2006	RH

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR